Notice of References Cited

Application/Control No. 10/767,628	Reexamination	Applicant(s)/Patent Under Reexamination BINNARD, MIKE		
Examiner	Art Unit			
Kevin Gutierrez	2851	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0075469 A1	06-2002	Tanaka, Keiichi	355/72
	В	US-2003/0184724 A1	10-2003	Ono et al.	355/72
	С	US-5,040,431	08-1991	Sakino et al.	74/490.09
	D	US-2004/0145715 A1	07-2004	Takashima, Tsuneo	355/072
	Ε	US-2003/0067592 A1	04-2003	Tim Poon et al.	355/75
	F	US-6,597,435 B2	07-2003	Poon et al.	355/75
	G	US-5,504,407 A	04-1996	Wakui et al.	318/568.17
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R		11			
	S					
	Т					

NON-PATENT DOCUMENTS

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
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